

DESIGN REVIEW

STURM2 SAMPLER OF TRANSIENTS FOR THE UNIFORMLY REDUNDANT MASK

Janne Himanen Jussi Kangaskoski

CONTENTS

- Overview
- Specification
- Block Diagram
- Problems / Solutions



OVERVIEW

- This device is a part of the KEKB particle accelerator upgrade and it is used to monitor electron beam bunches profile
- When electron beam is bended, it emits an X-ray beam and that's focused to the fermionics sensor
- The biggest challenge in this work is to get fast sampling and lots of gain to work in one device



Specifications

- The sampling speed of the device is 10 giga samples per second
- Input signal is $35 \mu V$
- At least 10 mV is needed in order to get the signal in a reasonable resolution



Specifications

- Analog input signal is amplified by 60dB with 3 x 20dB amplifier
- 8 ASICs x 8 channels x 3 amplifier stages = 192 amplifier cards



Specifications

- 8 ASIC cards which holds the STURM2 ASIC chip
- STURM2 cards makes an 12 bit analog / digital conversion



BLOCK DIAGRAM

Motherboard







- Footprint of the connectors on the motherboard and Daughter card was wrong
 - The gap between connectors legs was 0.7875mm → supposed to be 0.8mm



^{0.3937}mm - (-0.3937)mm = 0.7874mm

• Changed DCs regulator LD39015 (V4) to AP7333

• Simpler



• MBs regulator LT3020ED (V39) to AP7333

• Simpler



- Part of MBs top solder mask was missing
- Added more vias to MBs cooling areas for more reliability



• MBs 6PIN_MOLEX connector had wrong functions → made new decal



• Amplifiers works like wanted on the carrier board





3 AMPs in a row with 3x20dB attenuator



14

- Amplifiers cause oscillations
 - Need to provide shielding
- Firmware is incomplete
 - Work on getting it working

Work continues...

THANKS FOR ATTENDING